TOSHIBA 2SK3205

TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE ( $L^2$ - $\pi$ -MOS V)

# 2 S K 3 2 0 5

HIGH SPEED, HIGH VOLTAGE SWITCHING APPLICATIONS SWITCHING REGULATOR APPLICATIONS, DC-DC CONVERTER AND MOTOR DRIVE APPLICATIONS

## 4 V Gate Drive

Low Drain-Sorce ON Resistance :  $R_{DS(ON)} = 0.36 \Omega$  (Typ.)

High Forward Transfer Admittance :  $|Y_{fS}| = 4.5 \text{ S}$  (Typ.)

Low Leakage Current :  $I_{DSS} = 100 \,\mu\text{A}$  (Max.) ( $V_{DS} = 150 \,\text{V}$ )

Enhancement-Mode :  $V_{th} = 0.8 \sim 2.0 \text{ V} \text{ (V}_{DS} = 10 \text{ V}, I_D = 1 \text{mA)}$ 

## MAXIMUM RATINGS (Ta = 25°C)

CHARACTERIS	SYMBOL	RATING	UNIT		
Drain-Source Voltage	$v_{ m DSS}$	150	V		
Drain-Gate Voltage (RG	$v_{ m DGR}$	150	V		
Gate-Source Voltage	$v_{GSS}$	±20	V		
Drain Current	DC	$I_{\mathbf{D}}$	5	A	
	Pulse	$I_{\mathrm{DP}}$	20		
Drain Power Dissipation	$P_{\mathbf{D}}$	20	W		
Single Pulse Avalanche	EAS	71	mJ		
Avalanche Current	$I_{ m AR}$	5	A		
Repetitive Avalanche En	$\mathrm{E}_{\mathrm{AR}}$	2	mJ		
Channel Temperature	$\mathrm{T_{ch}}$	150	°C		
Storage Temperature Ra	$\mathrm{T_{stg}}$	-55~150	°C		

## THERMAL CHARACTERISTICS

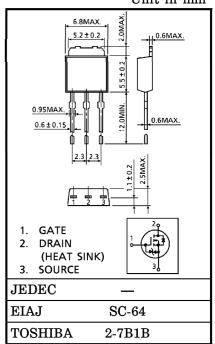
CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance, Channel to Case	R <sub>th (ch-c)</sub>	6.25	°C/W
Thermal Resistance, Channel to Ambient	R <sub>th (ch-a)</sub>	125	°C/W

## Note:

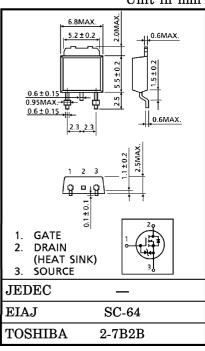
- \*  $V_{DD} = 50 \text{ V}, T_{ch} = 25^{\circ}\text{C}$  (initial), L = 4.2 mH, $I_{AR} = 5 A$ ,  $R_{G} = 25 \Omega$
- \*\* Repetitive rating; Pulse Width Limited by Max.

This transistor is an electrostatic sensitive device. Please handle with caution.

## INDUSTRIAL APPLICATIONS Unit in mm



### Unit in mm



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## ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARA	CTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakag	e Current	$I_{ m GSS}$	$V_{GS} = \pm 16  V,  V_{DS} = 0  V$	_	_	±10	$\mu$ <b>A</b>
Drain Cut-of		IDSS	$V_{DS} = 150 \text{ V}, V_{GS} = 0 \text{ V}$	_	_	100	$\mu \mathbf{A}$
Drain-Source Voltage	Breakdown		$I_{D} = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	150	_	_	V
Gate Thresho	old Voltage	$V_{ m th}$	$V_{\mathrm{DS}} = 10  \mathrm{V}, \; \mathrm{I}_{\mathrm{D}} = 1  \mathrm{mA}$	0.8	_	2.0	V
Drain-Source ON Resistance		R <sub>DS</sub> (ON)	$V_{GS} = 4 \text{ V}, I_D = 2.5 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$	_	0.54 0.36	0.75 0.5	Ω
Forward Tran Admittance	nsfer	Y <sub>fs</sub>	$V_{ m DS} = 10 \  m V, \ I_{ m D} = 2.5 \  m A$	2.0	4.5	_	S
Input Capaci	tance	$\mathrm{C}_{\mathrm{iss}}$			330	_	
Reverse Transfer Capacitance		$C_{rss}$	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1  MHz	_	50	_	pF
Output Capacitance		Coss		_	145	_	1
Switching Time Fall Time	Rise Time	t <sub>r</sub>	$V_{GS}^{10 \text{ V}} \prod_{P_1} I_D = 2.5 \text{ A} \text{VOUT}$	_	10	_	
	Turn-on Time	t <sub>on</sub>	$\begin{array}{c c} & & & \\ & & & \\ & & & \\ \end{array}$ $\begin{array}{c} & & \\ & & \\ \end{array}$	_	15	_	ns
	Fall Time	tf		_	10	_	115
	Turn-off Time	t <sub>off</sub>	$egin{aligned} V_{ ext{IN}}: t_{ ext{r}}, \ t_{ ext{f}} < 5 \  ext{ns}, \ U_{ ext{DD}} &= 100 \  ext{V} \  ext{Duty} &= 1\%, \ t_{ ext{W}} = 10 \ \mu  ext{s} \end{aligned}$	_	60	_	
Total Gate Charge (Gate- Source Plus Gate-Drain)		$\mathbf{Q}_{\mathrm{g}}$	$V_{DD} = 120 \text{ V}, V_{GS} = 10 \text{ V},$	_	12	_	
Gate-Source Charge		$Q_{\mathrm{gs}}$	$I_D = 5 A$	_	8	_	nC
Gate-Drain ("Miller") Charge		$\mathbf{Q}_{\mathbf{gd}}$		_	4	_	

# SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $Ta = 25^{\circ}C$ )

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Continuous Drain Reverse Current	$I_{ m DR}$	_	_	_	5	A
Pulse Drain Reverse Current	${ m I}_{ m DRP}$	_	_	_	20	A
Diode Forward Voltage	${ m v_{DSF}}$	$I_{DR} = 5 A$ , $V_{GS} = 0 V$	_	_	-1.7	V
Reverse Recovery Time	$t_{rr}$	$I_{DR} = 5 \text{ A}, V_{GS} = 0 \text{ V}$	_	110	_	ns
Reverse Recovery Charge	$Q_{rr}$	$\mathrm{dI}_{\mathrm{DR}}$ / $\mathrm{dt}=100\mathrm{A}$ / $\mu\mathrm{s}$	_	0.47	_	nC